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O.I.P.E.	PATENT DATE							
SCANNED AM QA. A.GT.								

APPLICATION NO. 09/686895		CLASS SUBCLASS		ART UNIT 2121	EXAMINER (Vor. B. h.
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Wen Kuo Yong Liao Chun Lin

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Smart automatic recording system and method for monitoring wafer fragmentation $\dot{}$

PTO-2040 12/99

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ISSUING CLASSIFICATION																							
ORIGINAL								 CROSS REFERENCE(S)															
CLASS SUBCLASS						CLA	ss	SUBCLASS (ONE SUBCLASS PER BLOCK)															
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INTERNATIONAL CLASSIFICATION																							
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TERMINAL		DRAWINGS		CLAIMS ALLOWED				
L. DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.			
☐ The term of this patent		<u>. </u>		NOTICE OF ALL	OWANCE MAILED			
subsequent to (date) has been disclaimed.	(Assistant	Examiner)	(Date)	,				
The term of this patent shall not extend beyond the expiration date								
of U.S Patent. No				ISSUE FEE				
				Amount Due	Date Paid			
	(Primary I	xaminer)	(Date)					
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uno patent nave been disclassico.	(Legal Instrume	ents Examiner)	(Date)					
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